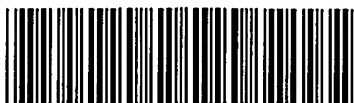


**Search Notes**

Application/Control No.

10/500,579

Examiner

Jinhee J. Lee

Applicant(s)/Patent under  
Reexamination

HIROSHI ET AL.

Art Unit

2831

**SEARCHED**

Class	Subclass	Date	Examiner
174	73.1	5/5/2005	LEE
<i>h</i>	75R	<i>h</i>	<i>h</i>
<i>h</i>	137R	<i>h</i>	<i>h</i>
174	as above	5/13/2006	LEE

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
174	as above	5/5/2005	LEE

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Updated Text search attached	10/14/2005	LEE